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▶ DRC Technology Crucial for Performing VPD Analysis at Balazs™ Analytical Services

The removal and control of metallic contaminants on the surface of silicon wafers, is an extremely important aspect of the semiconductor manufacturing process. During this high-temperature process, metals can diffuse rapidly into the silicon substrate and cause undesirable changes in the wafer's electrical characteristics, affecting both the performance and yield of the manufactured

devices. In fact, as little as 108 atoms/cm² of metallic contaminants on the surface of a silicon wafer can adversely affect manufacturing yields and increase device failure rates.

The most common approach used to measure these contamination levels is called Vapor Phase Decomposition, better known as the VPD technique.

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ICP-MS has gained popularity over the past twenty years, based mainly on its ability to rapidly quantitate at the ultratrace metal contamination level. However, in its basic design, ICP-MS cannot reveal anything about the metal's oxidation state, alkylated form or how it is bound to a bio-molecule. The desire

to understand in what form or species an element exists, has led researchers to investigate the combination of chromatographic separation devices with ICP-MS.

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▶ PerkinElmer and Arnel, Inc.-The Perfect Combination for the Best GC Separation

About the time that Microsoft® released MS DOS 5.0™ (1991), PerkinElmer and Arnel signed a cooperative engineering/marketing agreement to provide high-quality, reliable, turnkey solutions to the analytical community. This agreement brought together the company with the greatest experience in providing commercial GC systems – PerkinElmer – with

the company that is globally recognized as the application-specific valved-GC company – Arnel. This agreement encompassed a plan to jointly engineer and market complete systems and guaranteed solutions that met industry standards and requirements.

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▶ A Better Way to Analyze Fuel Diluents in Lubricating Oils

From a fairly early age, most of us learn that there are certain things that are best not done. As a kid, I soon caught on that trying to retrieve my dropped candy from the neighbor's boxer dog nearly resulted in my nick name being changed to Lefty. As I got older, I also was fairly quick to learn that asking my wife if she got a sizeable discount on her new hair style could cause me more pain

than could my neighbor's boxer. It could be said that analyzing fuel diluents in lubricating oils by flash-point analysis could fit into the same category as the items listed above. In the hope that time teaches how to do things better, we would like to discuss a new method for analyzing fuel diluents in lubricating oils using gas chromatography (GC).

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